



18. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

FCC ID: A3LSMN975U	 PCTEST ENGINEERING LABORATORY, INC.	HAC (RF EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename: 1M1905200079-17-R1.A3L	Test Dates: 06/17/2019 - 06/20/2019	DUT Type: Portable Handset	Page 122 of 124	

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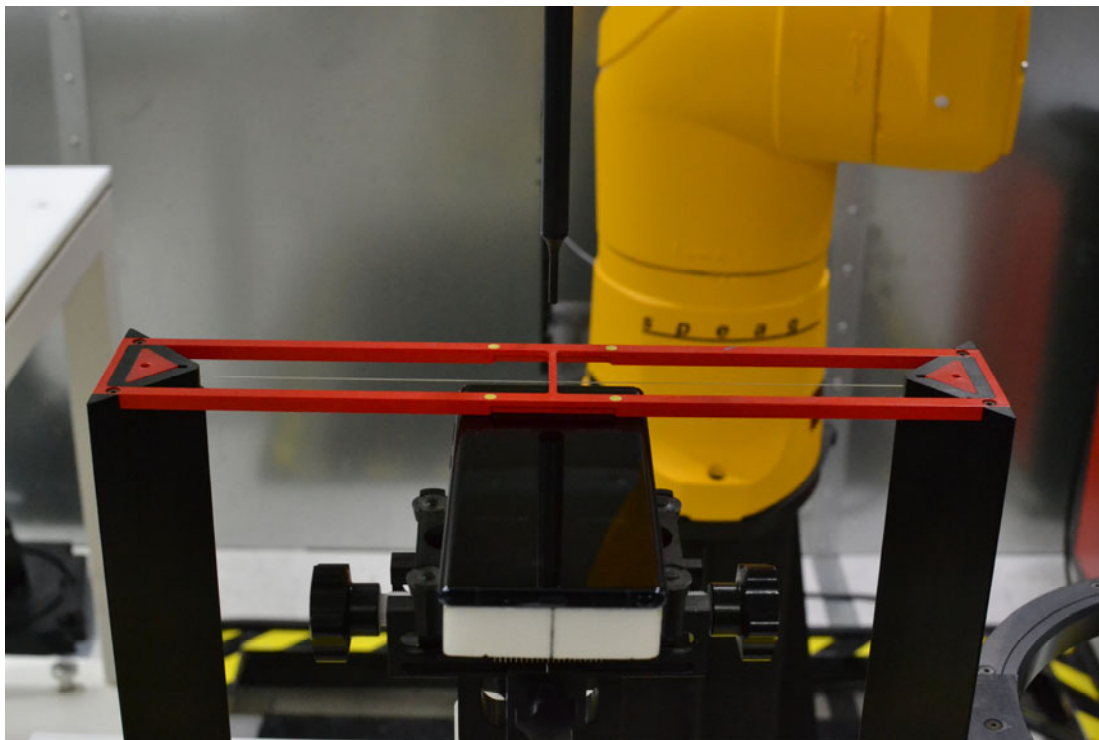


Figure 18-1
Ear Reference Point HAC Phantom Alignment

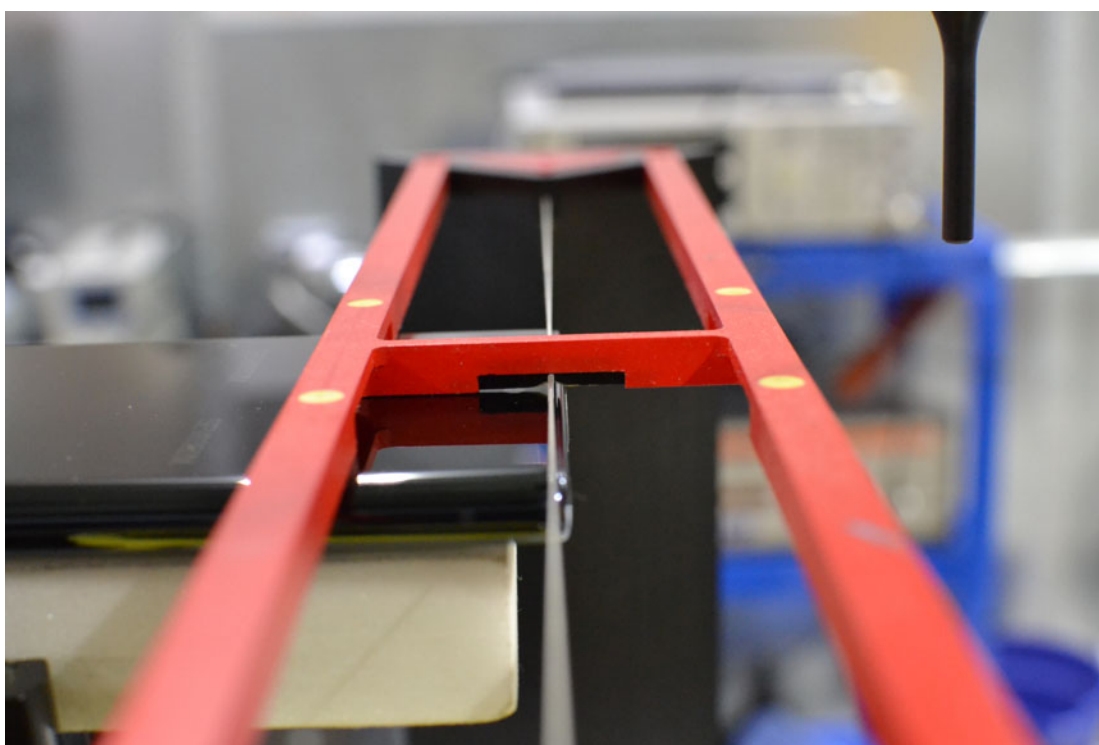




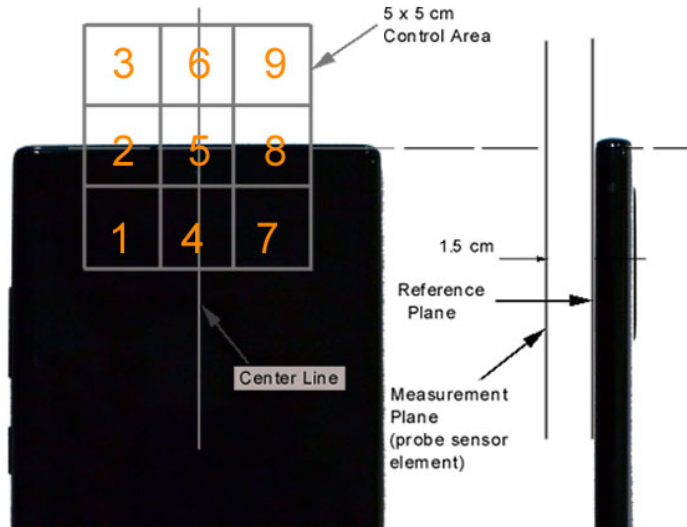
Figure 18-2
HAC Phantom Plane Alignment

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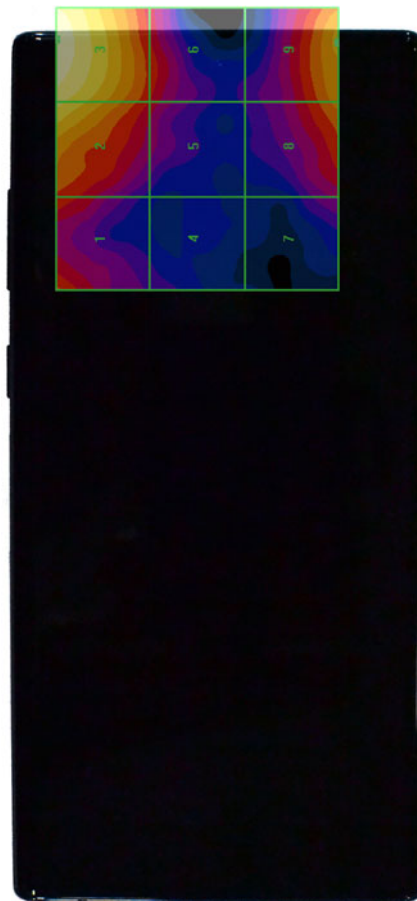
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**Figure 18-3 5x5 Scan grid above WD
(Acoustic Centered Scan Area pictured)**



**Figure 18-4 E-Field WD Scan overlay
(T-coil Centered Scan Area pictured)**

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